

**Notice of References Cited**

Application/Control No.

09/851,983

Applicant(s)/Patent Under  
Reexamination  
TOUI ET AL.

Examiner

Marc S. Zimmer

Art Unit

1712

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 60199074 A	10-1985	Japan	MIYOSAWA et al.	C09D 03/82
	O	JP 2000144049 A	05-2000	Japan	TAKEUCHI et al.	C09D175/04
	P					
	Q					
	R					
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**NON-PATENT DOCUMENTS**

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